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High-energy synchrotron X-rays for interface structures and material processing analysis

The European Synchrotron - Extremely Bright Source (ESRF-EBS) opens plenty of opportunities to study material structures with a resolution unachievable until now. In the beamline ID31 we take advantage of its full potential to conduct cutting-edge science. We use high-energy X-rays to study the biggest challenges of today's society. We are specialized in characterization techniques including reflectivity, wide and small angle diffraction (both in transmission and grazing incidence geometry), imaging methods, auxiliary techniques, coupled with a great versatility in choosing beam sizes, energy and energy-band.

The applications studied in our beamline range from batteries, catalytic systems, and other energy-related to metallurgy and additive manufacturing. In particular, my study focuses on the operando characterization of crystalline thin films and membranes to see how strain correlate with the electrocatalytic activity.

Please select the related topic from the list below

Instrumentation and methods

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